

ABSTRACT

Image observation at high resolution is realized and irregularity information of a sample is obtained.

5 The reflected electrons 12a emitted in a direction at a small angle with the surface of the sample 8 are detected by the detectors 10a and 10b arranged on the side of the electron source 1 of the magnetic field leakage type object lens 7 and a sample image is formed. Irregularity
10 information of the sample is obtained from the effects of light and shade appearing in the sample image.